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Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	32
Number of Macrocells	512
Number of Gates	10000
Number of I/O	176
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7512aeqc208-7n

Table 1. MAX 7000A Device Features

Feature	EPM7032AE	EPM7064AE	EPM7128AE	EPM7256AE	EPM7512AE
Usable gates	600	1,250	2,500	5,000	10,000
Macrocells	32	64	128	256	512
Logic array blocks	2	4	8	16	32
Maximum user I/O pins	36	68	100	164	212
t_{PD} (ns)	4.5	4.5	5.0	5.5	7.5
t_{SU} (ns)	2.9	2.8	3.3	3.9	5.6
t_{FSU} (ns)	2.5	2.5	2.5	2.5	3.0
t_{CO1} (ns)	3.0	3.1	3.4	3.5	4.7
f_{CNT} (MHz)	227.3	222.2	192.3	172.4	116.3

...and More Features

- 4.5-ns pin-to-pin logic delays with counter frequencies of up to 227.3 MHz
- MultiVolt™ I/O interface enables device core to run at 3.3 V, while I/O pins are compatible with 5.0-V, 3.3-V, and 2.5-V logic levels
- Pin counts ranging from 44 to 256 in a variety of thin quad flat pack (TQFP), plastic quad flat pack (PQFP), ball-grid array (BGA), space-saving FineLine BGA™, and plastic J-lead chip carrier (PLCC) packages
- Supports hot-socketing in MAX 7000AE devices
- Programmable interconnect array (PIA) continuous routing structure for fast, predictable performance
- PCI-compatible
- Bus-friendly architecture, including programmable slew-rate control
- Open-drain output option
- Programmable macrocell registers with individual clear, preset, clock, and clock enable controls
- Programmable power-up states for macrocell registers in MAX 7000AE devices
- Programmable power-saving mode for 50% or greater power reduction in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- Programmable security bit for protection of proprietary designs
- 6 to 10 pin- or logic-driven output enable signals
- Two global clock signals with optional inversion
- Enhanced interconnect resources for improved routability
- Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
- Programmable output slew-rate control
- Programmable ground pins

- Software design support and automatic place-and-route provided by Altera's development systems for Windows-based PCs and Sun SPARCstation, and HP 9000 Series 700/800 workstations
- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and VeriBest
- Programming support with Altera's Master Programming Unit (MPU), MasterBlaster™ serial/universal serial bus (USB) communications cable, ByteBlasterMV™ parallel port download cable, and BitBlaster™ serial download cable, as well as programming hardware from third-party manufacturers and any Jam™ STAPL File (.jam), Jam Byte-Code File (.jbc), or Serial Vector Format File- (.svf) capable in-circuit tester

General Description

MAX 7000A (including MAX 7000AE) devices are high-density, high-performance devices based on Altera's second-generation MAX architecture. Fabricated with advanced CMOS technology, the EEPROM-based MAX 7000A devices operate with a 3.3-V supply voltage and provide 600 to 10,000 usable gates, ISP, pin-to-pin delays as fast as 4.5 ns, and counter speeds of up to 227.3 MHz. MAX 7000A devices in the -4, -5, -6, -7, and some -10 speed grades are compatible with the timing requirements for 33 MHz operation of the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2*. See [Table 2](#).

Table 2. MAX 7000A Speed Grades

Device	Speed Grade					
	-4	-5	-6	-7	-10	-12
EPM7032AE	✓			✓	✓	
EPM7064AE	✓			✓	✓	
EPM7128A			✓	✓	✓	✓
EPM7128AE		✓		✓	✓	
EPM7256A			✓	✓	✓	✓
EPM7256AE		✓		✓	✓	
EPM7512AE				✓	✓	✓

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- Global clock signal. This mode achieves the fastest clock-to-output performance.
- Global clock signal enabled by an active-high clock enable. A clock enable is generated by a product term. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- Array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available in MAX 7000A devices. As shown in [Figure 1](#), these global clock signals can be the true or the complement of either of the global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in [Figure 2](#), the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear from the register are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active-low dedicated global clear pin (GCLRn). Upon power-up, each register in a MAX 7000AE device may be set to either a high or low state. This power-up state is specified at design entry. Upon power-up, each register in EPM7128A and EPM7256A devices are set to a low state.

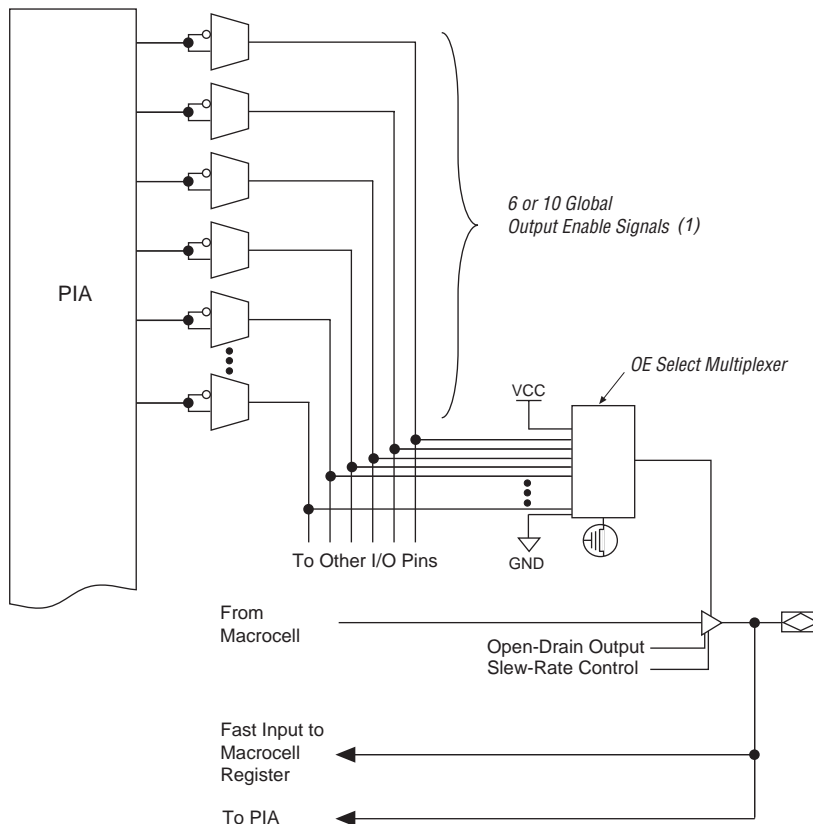
All MAX 7000A I/O pins have a fast input path to a macrocell register. This dedicated path allows a signal to bypass the PIA and combinatorial logic and be clocked to an input D flipflop with an extremely fast (as low as 2.5 ns) input setup time.

Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The compiler can allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by $2 \times t_{PEXP}$.

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest-numbered macrocell can only lend parallel expanders, and the highest-numbered macrocell can only borrow them. [Figure 4](#) shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 6. I/O Control Block of MAX 7000A Devices**Note:**

- (1) EPM7032AE, EPM7064AE, EPM7128A, EPM7128AE, EPM7256A, and EPM7256AE devices have six output enable signals. EPM7512AE devices have 10 output enable signals.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to V_{CC} , the output is enabled.

The MAX 7000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

In-System Programmability

MAX 7000A devices can be programmed in-system via an industry-standard 4-pin IEEE Std. 1149.1 (JTAG) interface. ISP offers quick, efficient iterations during design development and debugging cycles. The MAX 7000A architecture internally generates the high programming voltages required to program EEPROM cells, allowing in-system programming with only a single 3.3-V power supply. During in-system programming, the I/O pins are tri-stated and weakly pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k Ω .

MAX 7000AE devices have an enhanced ISP algorithm for faster programming. These devices also offer an ISP_Done bit that provides safe operation when in-system programming is interrupted. This ISP_Done bit, which is the last bit programmed, prevents all I/O pins from driving until the bit is programmed. This feature is only available in EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, and EPM7512AE devices.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a PCB with standard pick-and-place equipment before they are programmed. MAX 7000A devices can be programmed by downloading the information via in-circuit testers, embedded processors, the Altera MasterBlaster serial/USB communications cable, ByteBlasterMV parallel port download cable, and BitBlaster serial download cable. Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling. MAX 7000A devices can be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. A constant algorithm uses a pre-defined (non-adaptive) programming sequence that does not take advantage of adaptive algorithm programming time improvements. Some in-circuit testers cannot program using an adaptive algorithm. Therefore, a constant algorithm must be used. MAX 7000AE devices can be programmed with either an adaptive or constant (non-adaptive) algorithm. EPM7128A and EPM7256A device can only be programmed with an adaptive algorithm; users programming these two devices on platforms that cannot use an adaptive algorithm should use EPM7128AE and EPM7256AE devices.

The Jam Standard Test and Programming Language (STAPL), JEDEC standard JESD 71, can be used to program MAX 7000A devices with in-circuit testers, PCs, or embedded processors.

Table 7. MAX 7000A Stand-Alone Verification Times for Different Test Clock Frequencies

Device	f_{TCK}								Units
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	
EPM7032AE	0.00	0.01	0.01	0.02	0.04	0.09	0.18	0.36	s
EPM7064AE	0.01	0.01	0.02	0.04	0.07	0.18	0.35	0.70	s
EPM7128AE	0.01	0.02	0.04	0.07	0.14	0.34	0.68	1.36	s
EPM7256AE	0.02	0.03	0.08	0.15	0.30	0.75	1.49	2.98	s
EPM7512AE	0.03	0.06	0.15	0.30	0.60	1.49	2.97	5.94	s
EPM7128A (1)	0.08	0.14	0.29	0.56	1.09	2.67	5.31	10.59	s
EPM7256A (1)	0.13	0.24	0.54	1.06	2.08	5.15	10.27	20.51	s

Note to tables:

- (1) EPM7128A and EPM7256A devices can only be programmed with an adaptive algorithm; users programming these two devices on platforms that cannot use an adaptive algorithm should use EPM7128AE and EPM7256AE devices.

Programming with External Hardware



MAX 7000A devices can be programmed on Windows-based PCs with an Altera Logic Programmer card, the MPU, and the appropriate device adapter. The MPU performs continuity checks to ensure adequate electrical contact between the adapter and the device.

For more information, see the [Altera Programming Hardware Data Sheet](#).

The Altera software can use text- or waveform-format test vectors created with the Altera Text Editor or Waveform Editor to test the programmed device. For added design verification, designers can perform functional testing to compare the functional device behavior with the results of simulation.

Data I/O, BP Microsystems, and other programming hardware manufacturers provide programming support for Altera devices.



For more information, see [Programming Hardware Manufacturers](#).

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000A devices include the JTAG BST circuitry defined by IEEE Std. 1149.1. [Table 8](#) describes the JTAG instructions supported by MAX 7000A devices. The pin-out tables, available from the Altera web site (<http://www.altera.com>), show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Programmable Speed/Power Control

MAX 7000A devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000A device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power operation (i.e., with the Turbo Bit option turned off). As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{SEXP} , t_{ACL} , and t_{CPPW} parameters.

Output Configuration

MAX 7000A device outputs can be programmed to meet a variety of system-level requirements.

MultiVolt I/O Interface

The MAX 7000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 7000A devices to connect to systems with differing supply voltages. MAX 7000A devices in all packages can be set for 2.5-V, 3.3-V, or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCIO pins can be connected to either a 3.3-V or 2.5-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with VCCIO levels lower than 3.0 V incur a slightly greater timing delay of t_{OD2} instead of t_{OD1} . Inputs can always be driven by 2.5-V, 3.3-V, or 5.0-V signals.

Table 12 describes the MAX 7000A MultiVolt I/O support.

Table 12. MAX 7000A MultiVolt I/O Support						
V _{CCIO} Voltage	Input Signal (V)			Output Signal (V)		
	2.5	3.3	5.0	2.5	3.3	5.0
2.5	✓	✓	✓	✓		
3.3	✓	✓	✓		✓	✓

Power Sequencing & Hot-Socketing

Because MAX 7000A devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. The V_{CCIO} and V_{CCINT} power planes can be powered in any order.

Signals can be driven into MAX 7000AE devices before and during power-up (and power-down) without damaging the device. Additionally, MAX 7000AE devices do not drive out during power-up. Once operating conditions are reached, MAX 7000AE devices operate as specified by the user.

MAX 7000AE device I/O pins will not source or sink more than 300 μ A of DC current during power-up. All pins can be driven up to 5.75 V during hot-socketing, except the OE1 and GLCRn pins. The OE1 and GLCRn pins can be driven up to 3.6 V during hot-socketing. After V_{CCINT} and V_{CCIO} reach the recommended operating conditions, these two pins are 5.0-V tolerant.

EPM7128A and EPM7256A devices do not support hot-socketing and may drive out during power-up.

Design Security

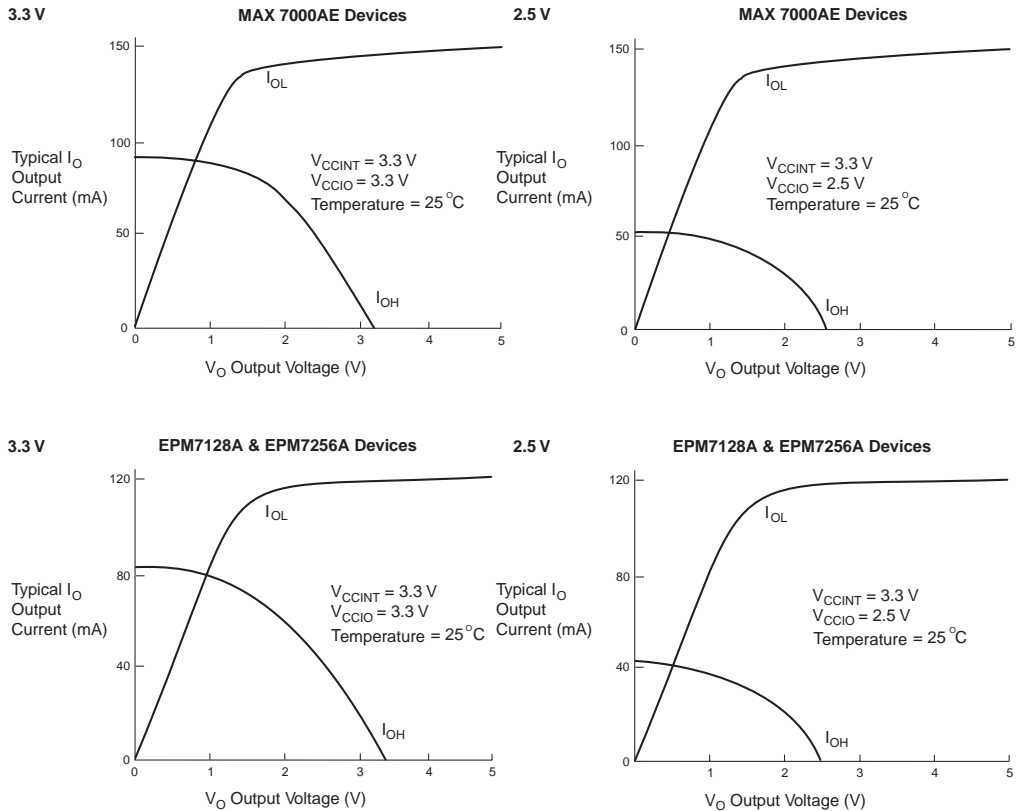
All MAX 7000A devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

Generic Testing

MAX 7000A devices are fully tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in [Figure 9](#). Test patterns can be used and then erased during early stages of the production flow.

Figure 10 shows the typical output drive characteristics of MAX 7000A devices.

Figure 10. Output Drive Characteristics of MAX 7000A Devices



Timing Model

MAX 7000A device timing can be analyzed with the Altera software, a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 11. MAX 7000A devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

Tables 17 through 30 show EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, EPM7512AE, EPM7128A, and EPM7256A timing information.

Table 17. EPM7032AE External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t _{SU}	Global clock setup time	(2)	2.9		4.7		6.3		ns
t _H	Global clock hold time	(2)	0.0		0.0		0.0		ns
t _{FSU}	Global clock setup time of fast input		2.5		3.0		3.0		ns
t _{FH}	Global clock hold time of fast input		0.0		0.0		0.0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t _{CH}	Global clock high time		2.0		3.0		4.0		ns
t _{CL}	Global clock low time		2.0		3.0		4.0		ns
t _{ASU}	Array clock setup time	(2)	1.6		2.5		3.6		ns
t _{AH}	Array clock hold time	(2)	0.3		0.5		0.5		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns
t _{ACH}	Array clock high time		2.0		3.0		4.0		ns
t _{ACL}	Array clock low time		2.0		3.0		4.0		ns
t _{CPPW}	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t _{CNT}	Minimum global clock period	(2)		4.4		7.2		9.7	ns
f _{CNT}	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz
t _{ACNT}	Minimum array clock period	(2)		4.4		7.2		9.7	ns
f _{ACNT}	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz

Table 20. EPM7064AE Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.6		1.1		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.6		1.1		1.4	ns
t_{FIN}	Fast input delay			2.5		3.0		3.7	ns
t_{SEXP}	Shared expander delay			1.8		3.0		3.9	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.5		2.5		3.2	ns
t_{LAC}	Logic control array delay			0.6		1.0		1.2	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.3		1.8	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		1.3		1.8		2.3	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.8		6.3		6.8	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.3		2.0		2.9		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{FSU}	Register setup time of fast input		1.0		1.5		1.5		ns
t_{FH}	Register hold time of fast input		1.5		1.5		1.5		ns
t_{RD}	Register delay			0.7		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.6		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.9		2.5	ns

Table 22. EPM7128AE Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		1.0		1.4	ns
t_{IO}	I/O input pad and buffer delay			0.7		1.0		1.4	ns
t_{FIN}	Fast input delay			2.5		3.0		3.4	ns
t_{SEXP}	Shared expander delay			2.0		2.9		3.8	ns
t_{PEXP}	Parallel expander delay			0.4		0.7		0.9	ns
t_{LAD}	Logic array delay			1.6		2.4		3.1	ns
t_{LAC}	Logic control array delay			0.7		1.0		1.3	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.2		1.6	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		1.3		1.7		2.1	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		5.8		6.2		6.6	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		4.5		4.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
t_{SU}	Register setup time		1.4		2.1		2.9		ns
t_H	Register hold time		0.6		1.0		1.3		ns
t_{FSU}	Register setup time of fast input		1.1		1.6		1.6		ns
t_{FH}	Register hold time of fast input		1.4		1.4		1.4		ns
t_{RD}	Register delay			0.8		1.2		1.6	ns
t_{COMB}	Combinatorial delay			0.5		0.9		1.3	ns
t_{IC}	Array clock delay			1.2		1.7		2.2	ns

Table 24. EPM7256AE Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t_{IC}	Array clock delay			1.2		1.6		2.1	ns
t_{EN}	Register enable time			0.8		1.0		1.3	ns
t_{GLOB}	Global control delay			1.0		1.5		2.0	ns
t_{PRE}	Register preset time			1.6		2.3		3.0	ns
t_{CLR}	Register clear time			1.6		2.3		3.0	ns
t_{PIA}	PIA delay	(2)		1.7		2.4		3.2	ns
t_{LPA}	Low-power adder	(6)		4.0		4.0		5.0	ns

Table 26. EPM7512AE Internal Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-12		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.7		0.9		1.0	ns
t_{IO}	I/O input pad and buffer delay			0.7		0.9		1.0	ns
t_{FIN}	Fast input delay			3.1		3.6		4.1	ns
t_{SEXP}	Shared expander delay			2.7		3.5		4.4	ns
t_{PEXP}	Parallel expander delay			0.4		0.5		0.6	ns
t_{LAD}	Logic array delay			2.2		2.8		3.5	ns
t_{LAC}	Logic control array delay			1.0		1.3		1.7	ns
t_{IOE}	Internal output enable delay			0.0		0.0		0.0	ns
t_{OD1}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		1.0		1.5		1.7	ns
t_{OD2}	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		1.5		2.0		2.2	ns
t_{OD3}	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or 3.3 V	$C1 = 35\text{ pF}$		6.0		6.5		6.7	ns
t_{ZX1}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		5.0		5.0	ns
t_{ZX2}	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		4.5		5.5		5.5	ns
t_{ZX3}	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		9.0		10.0		10.0	ns
t_{XZ}	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		5.0		5.0	ns
t_{SU}	Register setup time		2.1		3.0		3.5		ns
t_H	Register hold time		0.6		0.8		1.0		ns
t_{FSU}	Register setup time of fast input		1.6		1.6		1.6		ns
t_{FH}	Register hold time of fast input		1.4		1.4		1.4		ns
t_{RD}	Register delay			1.3		1.7		2.1	ns
t_{COMB}	Combinatorial delay			0.6		0.8		1.0	ns

Table 30. EPM7256A Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
t_{COMB}	Combinatorial delay			1.6		2.0		2.7		3.2	ns
t_{IC}	Array clock delay			2.7		3.4		4.5		5.4	ns
t_{EN}	Register enable time			2.5		3.1		4.2		5.0	ns
t_{GLOB}	Global control delay			1.1		1.4		1.8		2.2	ns
t_{PRE}	Register preset time			2.3		2.9		3.8		4.6	ns
t_{CLR}	Register clear time			2.3		2.9		3.8		4.6	ns
t_{PIA}	PIA delay	(2)		1.3		1.6		2.1		2.6	ns
t_{LPA}	Low-power adder	(6)		11.0		10.0		10.0		10.0	ns

Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in [Table 14 on page 28](#). See [Figure 12](#) for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
- (4) This parameter is measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) Operating conditions: $V_{CCIO} = 2.5 \pm 0.2$ V for commercial and industrial use.
- (6) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{SEXP} , t_{ACL} , and t_{CPPW} parameters for macrocells running in low-power mode.

Power Consumption

Supply power (P) versus frequency (f_{MAX} , in MHz) for MAX 7000A devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The P_{IO} value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*.

The I_{CCINT} value depends on the switching frequency and the application logic. The I_{CCINT} value is calculated with the following equation:

$$I_{CCINT} = (A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times f_{MAX} \times \log_{LC})$$

The parameters in this equation are:

- MC_{TON} = Number of macrocells with the Turbo Bit option turned on, as reported in the MAX+PLUS II Report File (.rpt)
 MC_{DEV} = Number of macrocells in the device
 MC_{USED} = Total number of macrocells in the design, as reported in the Report File
 f_{MAX} = Highest clock frequency to the device
 to_{gLC} = Average percentage of logic cells toggling at each clock (typically 12.5%)
A, B, C = Constants, shown in [Table 31](#)

Table 31. MAX 7000A I_{CC} Equation Constants

Device	A	B	C
EPM7032AE	0.71	0.30	0.014
EPM7064AE	0.71	0.30	0.014
EPM7128A	0.71	0.30	0.014
EPM7128AE	0.71	0.30	0.014
EPM7256A	0.71	0.30	0.014
EPM7256AE	0.71	0.30	0.014
EPM7512AE	0.71	0.30	0.014

This calculation provides an I_{CC} estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual I_{CC} should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figure 21. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.

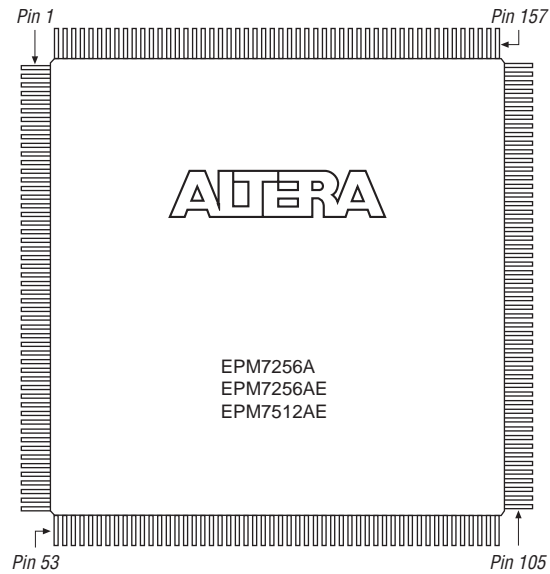
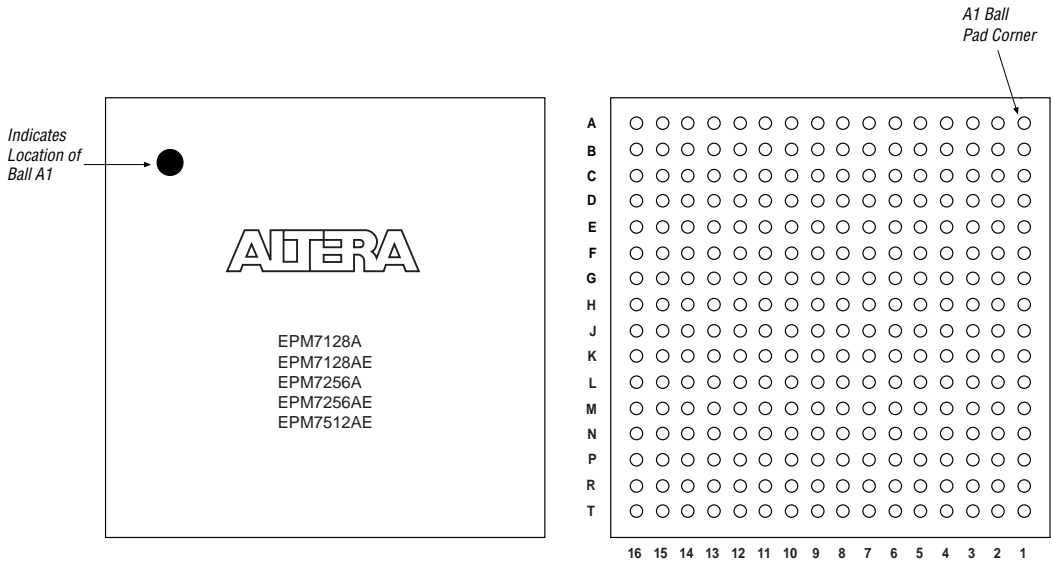


Figure 23. 256-Pin FineLine BGA Package Pin-Out Diagram

Package outline not drawn to scale.



Revision History

The information contained in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5 supersedes information published in previous versions.

Version 4.5

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5:

- Updated text in the “Power Sequencing & Hot-Socketing” section.

Version 4.4

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.4:

- Added Tables 5 through 7.
- Added “Programming Sequence” on page 17 and “Programming Times” on page 18.

Version 4.3

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.3:

- Added extended temperature devices to document
- Updated [Table 14](#).

Version 4.2

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.2:

- Removed *Note (1)* from [Table 2](#).
- Removed *Note (4)* from [Tables 3](#) and [4](#).

Version 4.1

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.1:

- Updated leakage current information in [Table 15](#).
- Updated [Note \(9\)](#) of [Table 15](#).
- Updated [Note \(1\)](#) of [Tables 17](#) through [30](#).



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